MOSFET – Power, Single N-Channel, Logic Level SO-8FL 30 V, 0.67 mΩ, 370 A

Features

- Small Footprint (5x6 mm) for Compact Design
- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- NVMFS4C01NWF Wettable Flanks Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

| Parameter | | | Symbol | Value | Unit |
|--|--|-----------------------|-----------------------------------|---------------|------|
| Drain-to-Source Voltage | | | V _{DSS} | 30 | V |
| Gate-to-Source Voltage | 9 | | V _{GS} | ±20 | V |
| Continuous Drain Current $R_{\theta JC}$ (Notes 1, 3) | Steady | T _C = 25°C | Ι _D | 370 | Α |
| Power Dissipation $R_{\theta JC}$ (Notes 1, 3) | State | T _C = 25°C | P _D | 161 | W |
| Continuous Drain Current $R_{\theta JA}$ (Notes 1, 2, 3) | Steady State | T _A = 25°C | I _D | 57 | Α |
| Power Dissipation $R_{\theta JA}$ (Notes 1, 2, 3) | Glale | T _A = 25°C | P _D | 3.84 | W |
| Pulsed Drain Current | Drain Current $T_A = 25^{\circ}C$, $t_p = 10 \mu s$ | | | 900 | Α |
| Operating Junction and Storage Temperature | | | T _J , T _{stg} | -55 to 175 | °C |
| Source Current (Body Diode) | | | I _S | 110 | Α |
| Single Pulse Drain-to-Source Avalanche Energy (I _{L(pk)} = 35 A) | | | E _{AS} | 862 | mJ |
| Lead Temperature for Soldering Purposes (1/8" from case for 10 s) | | | TL | 260 | °C |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS (Note 1)

| Parameter | Symbol | Value | Unit |
|---|-----------------|-------|------|
| Junction-to-Case - Steady State | $R_{\theta JC}$ | 0.93 | °C/W |
| Junction-to-Ambient - Steady State (Note 2) | $R_{\theta JA}$ | 39 | |

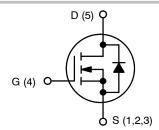
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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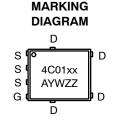
www.onsemi.com

| V _{(BR)DSS} | R _{DS(ON)} MAX | I _D MAX |
|----------------------|-------------------------|--------------------|
| 30 V | 0.67 m Ω @ 10 V | 070 4 |
| 30 V | 0.95 m Ω @ 4.5 V | 370 A |



N-CHANNEL MOSFET





4C01N = Specific Device Code for NVMFS4C01N

4C01WF= Specific Device Code of NVMFS4C01NWF

A = Assembly Location

′ = Year

W = Work Week

ZZ = Lot Traceability

ORDERING INFORMATION

| Device | Package | Shipping [†] |
|-----------------|----------------------|-----------------------|
| NVMFS4C01NT1G | SO-8 FL (Pb-Free) | 1500 / Tape & Reel |
| NVMFS4C01NT3G | SO-8 FL (Pb-Free) | 5000 / Tape & Reel |
| NVMFS4C01NWFT1G | SO-8 FL (Pb-Free) | 1500 / Tape & Reel |
| NVMFS4C01NWFT3G | SO-8 FL (Pb-Free) | 5000 / Tape & Reel |

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise specified)

| Parameter | Symbol | Test Condition | | Min | Тур | Max | Unit |
|--|-------------------------------------|---|------------------------|-----|----------|------|-------|
| OFF CHARACTERISTICS | - | | | - | <u> </u> | | |
| Drain-to-Source Breakdown Voltage | V _{(BR)DSS} | V_{GS} = 0 V, I_{D} = 250 μA | | 30 | | | V |
| Drain-to-Source Breakdown Voltage Temperature Coefficient | V _{(BR)DSS} / | | | | 16.3 | | mV/°C |
| Zero Gate Voltage Drain Current | I _{DSS} | $V_{GS} = 0 V$ | T _J = 25 °C | | | 1 | |
| | | V _{DS} = 24 V T _J = 125°C | | | | 100 | μΑ |
| Gate-to-Source Leakage Current | I _{GSS} | V _{DS} = 0 V, V _{GS} = 20 V | | | | 100 | nA |
| ON CHARACTERISTICS (Note 4) | | | | | | | |
| Gate Threshold Voltage | V _{GS(TH)} | $V_{GS} = V_{DS}, I_D$ | = 250 μΑ | 1.3 | | 2.2 | V |
| Negative Threshold Temperature Coefficient | V _{GS(TH)} /T _J | | | | 5.8 | | mV/°C |
| Drain-to-Source On Resistance | R _{DS(on)} | V _{GS} = 10 V | I _D = 30 A | | 0.56 | 0.67 | |
| | | V _{GS} = 4.5 V | I _D = 30 A | | 0.76 | 0.95 | mΩ |
| Forward Transconductance | 9FS | $V_{DS} = 3 \text{ V, } I_{D}$ | = 30 A | | 183 | | S |
| Gate Resistance | R_{G} | T _A = 25 °C | | | 1.0 | | Ω |
| CHARGES AND CAPACITANCES | | | | | | | |
| Input Capacitance | C _{ISS} | V _{GS} = 0 V, f = 1 MHz, V _{DS} = 15 V | | | 10144 | | pF |
| Output Capacitance | C _{OSS} | | | | 5073 | | |
| Reverse Transfer Capacitance | C _{RSS} | | | | 148 | | |
| Total Gate Charge | Q _{G(TOT)} | | | | 63 | | |
| Threshold Gate Charge | Q _{G(TH)} | V _{GS} = 4.5 V, V _{DS} = 15 V; I _D = 30 A | | | 18 | | nC |
| Gate-to-Source Charge | Q _{GS} | | | | 29 | | |
| Gate-to-Drain Charge | Q_{GD} | 1 | | | 13 | | 1 |
| Total Gate Charge | Q _{G(TOT)} | V _{GS} = 10 V, V _{DS} = 15 V, I _D = 30 A | | | 139 | | nC |
| SWITCHING CHARACTERISTICS (Note 5) | | | | • | • | | |
| Turn-On Delay Time | t _{d(ON)} | | | | 29 | | |
| Rise Time | t _r | $V_{GS} = 4.5 \text{ V}, V_{DS} = 15 \text{ V}, I_{D} = 15 \text{ A},$ $R_{G} = 3.0 \Omega$ | | | 68 | | ns |
| Turn-Off Delay Time | t _{d(OFF)} | | | | 53 | | |
| Fall Time | t _f | | | | 36 | | |
| DRAIN-SOURCE DIODE CHARACTERISTIC | cs | • | | | | | • |
| Forward Diode Voltage | V_{SD} | V _{GS} = 0 V, | T _J = 25°C | | 0.73 | 1.1 | V |
| | | I _S = 10 A | T _J = 125°C | | 0.55 | | |
| Reverse Recovery Time | t _{RR} | $V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$ | | | 87 | | |
| Charge Time | ta | | | | 43 | | ns |
| | | | | | | | 1 |
| Discharge Time | t _b | I _S = 30 | A | | 44 | | |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width $\leq 300~\mu s$, duty cycle $\leq 2\%$.

5. Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

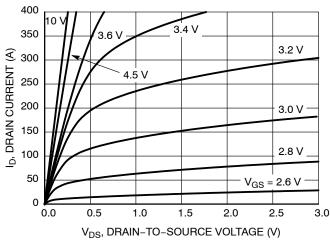


Figure 1. On-Region Characteristics

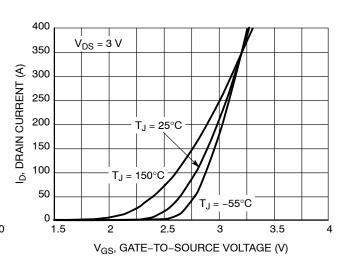


Figure 2. Transfer Characteristics

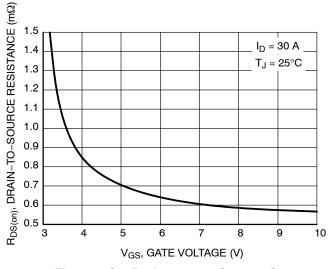


Figure 3. On-Resistance vs. Gate-to-Source Voltage

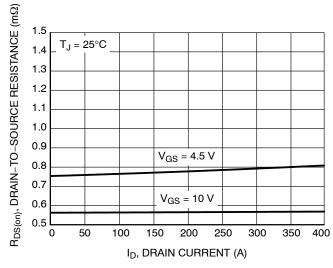


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

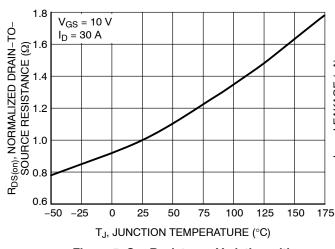


Figure 5. On–Resistance Variation with Temperature

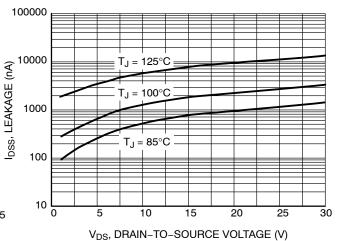


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL CHARACTERISTICS

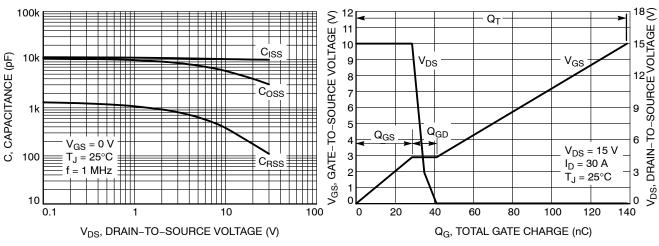


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

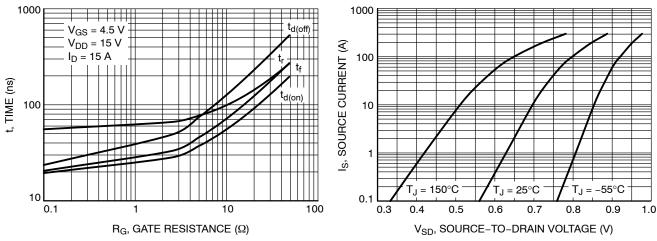


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

Figure 10. Diode Forward Voltage vs. Current

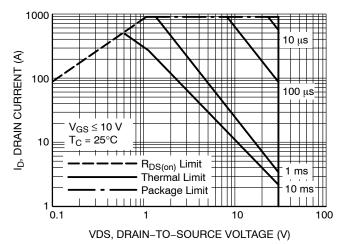


Figure 11. Maximum Rated Forward Biased Safe Operating Area

TYPICAL CHARACTERISTICS

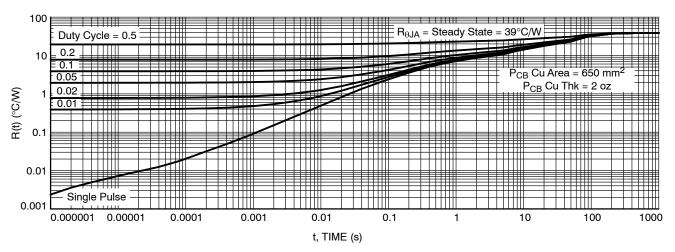


Figure 12. Thermal Impedance (Junction-to-Ambient)

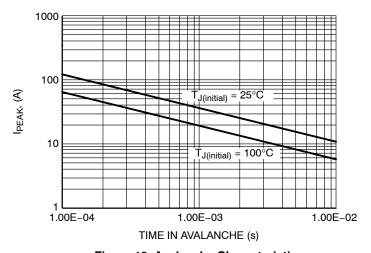


Figure 13. Avalanche Characteristics



0.10

0.10

SIDE VIEW

DFN5 5x6, 1.27P (SO-8FL) CASE 488AA ISSUE N

DATE 25 JUN 2018

NOTES:

BURRS

- DIMENSIONING AND TOLERANCING PER
- ASME Y14.5M, 1994.
 CONTROLLING DIMENSION: MILLIMETER.
 DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

| | MILLIMETERS | | | | |
|-----|-------------|-------|------|--|--|
| DIM | MIN | NOM | MAX | | |
| Α | 0.90 | 1.00 | 1.10 | | |
| A1 | 0.00 | | 0.05 | | |
| b | 0.33 | 0.41 | 0.51 | | |
| С | 0.23 | 0.28 | 0.33 | | |
| D | 5.00 | 5.15 | 5.30 | | |
| D1 | 4.70 | 4.90 | 5.10 | | |
| D2 | 3.80 | 4.00 | 4.20 | | |
| E | 6.00 | 6.15 | 6.30 | | |
| E1 | 5.70 | 5.90 | 6.10 | | |
| E2 | 3.45 | 3.65 | 3.85 | | |
| е | 1.27 BSC | | | | |
| G | 0.51 | 0.575 | 0.71 | | |
| K | 1.20 | 1.35 | 1.50 | | |
| L | 0.51 | 0.575 | 0.71 | | |
| L1 | 0.125 REF | | | | |
| M | 3.00 | 3.40 | 3.80 | | |
| A | 0 0 | | 12 ° | | |

GENERIC MARKING DIAGRAM*



XXXXXX = Specific Device Code

= Assembly Location Α

Υ = Year W = Work Week ZZ = Lot Traceability

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present. Some products may not follow the Generic Marking.





DETAIL A

*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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| DESCRIPTION: | DFN5 5x6, 1.27P (SO-8FL) | | PAGE 1 OF 1 | |

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